## **Başkent University Department of Electrical and Electronics Engineering EEM 214 Electronics I Experiment 8**

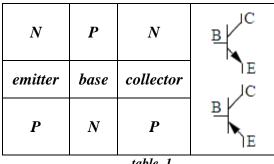
### **Bipolar Junction Transistor**

#### Aim:

The aim of this experiment is to investigate the DC behavior of a bipolar junction transistor (BJT) in a common emitter circuit configuration in Fig.1.

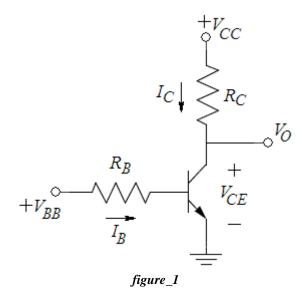
#### **Theory:**

Like MOSFET, it is another type of transistor with three terminals: Base (B), Collector (C) and Emitter (E). The BJT can either be an NPN or a PNP. General configuration and the circuit symbol of both of the type of BJTs shown at *table\_1*.



table\_1

Unlike MOSFETs, total current in BJTs consist of both Electron and Hole current. BJT is regarded as a current-controlled-current device where the quantity of the base current controls the flow of current from collector to emitter or vice versa.



At the input side, the base current  $I_B$  is determined by  $V_{BB}$  and  $R_B$ . When  $V_{BB} < V_{BE(ON)}$ , the transistor is in cut-off (OFF) state, and we have  $I_B = 0$ . When  $V_{BB} > V_{BE(ON)}$ , the base current can be found as

$$I_{B} = \frac{V_{BB} - V_{BE(ON)}}{R_{B}}$$

from the loop equation at the input side. In this case the transistor might be in forward-active (ACT) or saturated (SAT) state, depending on the values of  $I_C$  and  $V_{CE}$ .

At the output side, the load line given by the output loop equation

$$V_{CC} = R_C . i_C + v_{CE}$$

determines the behavior of the circuit in Fig.1. For a given base current  $I_B$  (calculated at the input side), the intersection of the load line with the transistor  $i_{C^-}v_{CE}$  curve determines the operating point (Q-point) and the state of the transistor. If this intersection point is in the "constant current" region of the transistor characteristics, the transistor is in ACT state,  $I_C = \beta I_B$ , and  $V_{CE} > V_{CE(SAT)}$ , Otherwise, the transistor is in SAT state,  $V_{CE} \approx V_{CE(SAT)}$  and from the output loop we have

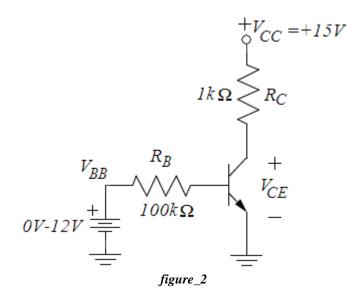
$$I_C = \frac{V_{CC} - V_{CE(SAT)}}{R_C}$$

;where  $I_C < \beta I_B$ .

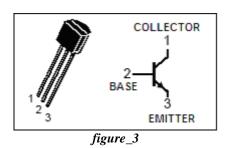
#### **Preliminary Work:**

Review Section 5 till section 5.10 in the textbook.

In laboratory you will construct the circuit in Fig.2 using the transistor BC238B.



The BC238B has a 200<  $\beta$  <320,  $V_{CE(SAT)} = 0.2$ V,  $V_{BE(ON)} = 0.6$ V and  $V_A = 100$ . Use V<sub>T</sub>=25mV and emission coefficient as n = 1 even though BC238B transistors may exhibit an emission coefficient in the range (1 \le n \le 2). The Pin Diagram of the BC238B is in Fig.3



At the input side, a variable voltage source is used to set  $V_{BB}$  to any desired value between 0 V and 12 V. The base current  $I_B$  can be adjusted by changing  $V_{BB}$  in this range. (In the experiment, you will measure  $I_B$  by measuring the voltage drop across the 100 K $\Omega$  resistor, and the particular value of  $V_{BB}$  that yields this  $I_B$  value will not be that important.)

1) Determine the range of  $I_B$  values that can be obtained with  $0 \le V_{BB} \le 12$  V. Take  $V_{BE(ON)} = 0.6$  V.

At the output side, the load line  $V_{CC} = R_C.i_C + v_{CE}$  together with the transistor  $i_C$ - $v_{CE}$  characteristics determine the behavior of the circuit. The transistor characteristics depend on  $\beta$  of the transistor. The  $\beta$  value of a given type of transistor may vary in a large range from transistor to transistor. The transistors that you are going to use in the laboratory will have  $200 < \beta < 320$ . In this preliminary work section, you will make some calculations with taking  $\beta = 260$ . However,  $\beta$  of the actual transistor that you will use in the laboratory will most likely be different. Therefore, your measurements in the laboratory will not yield the same values as those in the preliminary work. In the following, take  $\beta = 260$  and  $V_{CE(SAT)} = 0.2$  V.

- 2) Draw the transistor  $i_C$ – $v_{CE}$  characteristics (piecewise linear model) for  $I_B = 0\mu$ A to  $I_B = 100\mu$ A in  $20\mu$ A steps. On the same graph, draw the load lines for  $R_C = 1$ k $\Omega$  and  $V_{CC} = 15$ V,  $V_{CC} = 10$ V,  $V_{CC} = 5$ V, and  $V_{CC} = 1$ V. Make sure that your graph is to scale and labeled properly.
- 3) Repeat the previous step for  $R_C = 2.2k\Omega$ . on a separate graph.

Note that the values of  $V_{CC}$ ,  $R_C$ , and  $I_B$  all influence the state of the transistor and the output voltage  $V_{CE}$ .

In the laboratory, you will first change  $I_B$  and measure  $I_C$ , keeping  $R_C = 1 \text{k}\Omega$  and  $V_{CC} = 15 \text{V}$  fixed. When the transistor is in ACT state, these two currents are related by  $I_C = \beta I_B$ . However, increasing  $I_B$  beyond a certain value pushes the transistor into saturation.

- 4) Determine the value of  $I_B$  that pushes the transistor into saturation. Take  $R_C = 1 \text{ k}\Omega$  and  $V_{CC} = 15\text{V}$ .
- 5) Repeat the previous step for  $R_C = 2.2k\Omega$ .

In the laboratory, you will also trace the transistor  $i_C$ — $v_{CE}$  characteristics at a constant value of  $I_B$  by changing  $V_{CC}$ . You can see how this works by inspecting the graphs of parts 2 and 3. At a fixed value of  $I_B$ , changing  $V_{CC}$  moves the Q-point along the constant  $I_B$  curve. Measuring  $I_C$  and  $V_{CE}$  as  $V_{CC}$  is decreased from 15V to 0V traces the entire transistor characteristics (both ACT and SAT regions) for that particular fixed value of  $I_B$ .

6) List and explain all the differences between the piecewise linear model and the actual  $i_B-v_{BE}$  and  $i_C-v_{CE}$  characteristics of a real transistor, considering all of the possible transistor states in this circuit (OFF, ACT, and SAT).

The PSPICE model for the BC238B transistor has to be included into your PSPICE installation before you can do the next step. Please refer to the WORD Document, that you downloaded, for instructions on how to do this. The  $\beta$  of the transistor in the PSPICE model is approximately 310-330.

- 7) Simulate the BJT circuit using PSPICE with  $R_C = 1k\Omega$  and  $V_{CC} = 15V$ . Generate a graph of output voltage  $V_{CE}$  versus input voltage  $V_{BB}$ , where  $V_{BB}$  ranges between 0V and 12V. (Use DC Sweep for this purpose.) On the graph, indicate the regions where the transistor is OFF, ACT, and SAT.
- 8) Zoom in at the SAT region so that small changes in  $V_{CE}$  as  $V_{BB}$  increases can be clearly seen. Comment on your results.

#### **Experimental Work:**

Before constructing the circuit, verify the values of the resistors that you are going to use by measuring their resistances with a multimeter. Make sure that all resistors are within 2% of their marked values. This will assure that your current measurements are accurate.

Construct the circuit given in the preliminary work section using  $R_C = 1 \text{k}\Omega$ . Set  $V_{CC} = 15 \text{V}$ . Make sure that  $V_{BB}$  can be adjusted in the 0 V to 12 V range.

During the entire experiment, to measure  $I_B$  first measure the voltage drop across the  $100k\Omega$  base resistor with a multimeter, and then divide this value by  $100k\Omega$ . Similarly, measure  $I_C$  by first measuring the voltage drop over  $R_C$  and then dividing this by  $R_C$ .

1) Set  $I_B = 0\mu$ A. Measure  $I_C$  and  $V_{CE}$ . What is the state of the transistor?

$$I_C = V_{CE} =$$

2) You will first measure the  $\beta$  of this transistor at various values of  $I_B$ . Set  $I_B = 5\mu A$  to  $I_B = 40\mu A$  in  $5\mu A$  steps. For each value of  $I_B$ , measure  $I_C$  and  $V_{CE}$ , make sure that the transistor is not SAT by comparing  $V_{CE}$  with  $V_{CE(SAT)}$ , and calculate  $\beta$ . Transistor  $\beta$  measured like this may depend on  $I_B$  to some extent (a difference between the actual device and its model). Find the average  $\beta$  value using the eight  $\beta$  values that you measured. In the rest of the experiment, use this average  $\beta$  value.

$I_B$	$I_B$	$I_C$	$V_{CE}$	β
5μ				
10μ				
15μ				
20μ				
25μ				
30μ				
35μ				
40μ				

3) Using the data that you took in the previous part, plot  $I_C$  versus  $V_{CE}$ . Fit a straight line to your data and determine the axis crossings. Make sure that your graph is to scale and labeled properly. What does the resulting straight line represent?

4) You will now see how increasing  $I_B$  pushes the transistor into saturation. Set  $I_B = 50\mu$ A to  $I_B = 100\mu$ A to in  $10\mu$ A steps. For each value of  $I_B$ , measure  $I_C$  and  $V_{CE}$ , and determine the state of the transistor by comparing  $I_C/I_B$  with  $\beta$ . How does  $V_{CE}$  compare with  $V_{CE(SAT)}$  before and after saturation? Note the differences between the model and the actual behavior of the transistor.

$I_B$	$I_C$	$V_{CE}$	$I_C/I_B$
50μ			
60μ			
70μ			
80μ			
90μ			
100μ			

- 5) Include the data points that you took in the previous part to the  $I_C$  versus  $V_{CE}$  plot of part 3. Has the straight line behavior changed in any way?
- 6) You will now trace the transistor  $i_C$ – $v_{CE}$  characteristics at a constant base current of  $I_B = 20 \mu A$ . This can be done by changing  $V_{CC}$  to sweep the load line as you measure  $I_C$ . and  $V_{CE}$ . Starting from  $V_{CC}$ =15V, decrease  $V_{CC}$  in steps that are not larger than 1 V, and measure  $I_C$ . and  $V_{CE}$  at each point. Take closer data points once in the SAT region. Plot your data on a graph paper.

$V_{CC}$	$I_C$	$V_{CE}$
15V		
14V		
13V		
12V		
11V		
10V		
9V		
8V		
7V		
6V		
5V		
4V		
3V		
2V		
1V		

- 7) Using the data of the previous part, determine the Early voltage  $V_A$ . To do this, you will have to calculate the slope of the  $i_C$ – $v_{CE}$  curve in the ACT region, and determine where this line crosses the horizontal ( $v_{CE}$ ) axis.
- 8) You will now investigate how changing the slope of the load line by changing  $R_C$  affects the circuit. Replace  $R_C$  with a  $2.2k\Omega$  resistor. Set  $I_B=5\mu$  to  $I_B=70\mu$  in  $5\mu$ A steps. For each value of  $I_B$ , measure  $I_C$  and  $V_{CE}$ , and determine the state of the transistor by comparing  $I_C/I_B$  with  $\beta$ . Plot this data on the graph of parts 3 and 5. How does changing  $R_C$  influence the  $I_B$  value that pushes the transistor into SAT?

$I_B$	$I_B$	$I_C$	$V_{CE}$	$I_C/I_B$
5μ				
10μ				
15μ				
20μ				
25μ				
30μ				
35μ				
40μ				
50μ				
60μ				
70μ				

Lab Instruments:	Components:
Breadboard	BC238B <i>npn</i> transistor
Multimeter	100 kΩ
DC Power Supply	1 kΩ
	2.2 kΩ

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# **Experiment Results**

$I_B$	$I_B$	$I_C$	V <sub>CE</sub>	β
5μ				
10μ				
15μ				
20μ				
25μ				
30μ				
35μ				
40μ				

$I_B$	$I_C$	$V_{CE}$	$I_C/I_B$
50μ			
60μ			
70μ			
80μ			
90μ			
100μ			

$I_B$	$I_B$	$I_C$	$V_{CE}$	$I_C/I_B$
5μ				
10μ				
15μ				
20μ				
25μ				
30μ				
35μ				
40μ				
50μ				
60μ				
70μ				

$V_{CC}$	$I_C$	$V_{CE}$
15V		
14V		
13V		
12V		
11V		
10V		
9V		
8V		
7V		
6V		
5V		
4V		
3V		
2V		
1V		

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